MSKSEMI 美森科













ESD

TSS

MOV

GDT

PIFD

2N7002W

Product specification





Features

- 60V,200mA,RDS(ON) =1.7 Ω @VGS = 10V
- Fast switching
- Green Device Available

BVDSS RDSON ID 60V 1.7Ω 200mA

Reference News

- Notebook
- Smartphone
- Battery Protection
- Hand-held Instruments

Reference News

PACKAGE OUTLINE	PIN Configuration	Marking
D	G	72*
SOT-323	S	

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V _D s	Drain-Source Voltage	60	V
Vgs	Gate-Source Voltage	±20	V
	Drain Current - Continuous (T _A =25°C) 200		mA
ID	Drain Current - Continuous (T₄=70°C)	160	mA
Ідм	Drain Current - Pulsed ¹ 800		mA
Do	Power Dissipation (T _A =25°C) 156		mW
PD	Po Power Dissipation - Derate above 25°C		mW/°C
Тѕтс	Storage Temperature Range	-55 to 150	
TJ	Operating Junction Temperature Range	-55 to 150 °C	

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		800	°C/W



Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	Vgs=0V , Ip=250uA	60			V
	Drain Source Leekage Current	VDS=60V , VGS=0V , TJ=25°C			10	nA
IDSS	Drain-Source Leakage Current	VDS=48V , VGS=0V , TJ=125°C			100	nA
Igss	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±100	nA

On Characteristics

R _{DS(ON)} Static Drain-Source On-Resista	Static Drain Source On Registenes	Vgs=10V , Ip=0.15A	-	1.6	3	
	Static Drain-Source On-Resistance	Vgs=4.5V , ID=0.1A		1.7	4	Ω
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.0	2	3.0	V
gfs	Forward Transconductance	V _{DS} = 10V , I _D =0.1A		0.3		S

Dynamic and switching Characteristics

- ymanno am	a switching offaractoristics				
Qg	Total Gate Charge ^{2,3}			2	
Qgs	Gate-Source Charge ^{2, 3}	VDS=30V , VGS=10V , ID=0.1A		0.9	 nC
Qgd	Gate-Drain Charge ^{2, 3}			0.4	
T _{d(on)}	Turn-On Delay Time ^{2, 3}			3	
Tr	Rise Time ^{2, 3}	Vpp=30V , Vgs=10V ,		5	
Td(off)	Turn-Off Delay Time ^{2, 3}	R _G =6Ω l _D =0.1A		14	 ns
Tf	Fall Time ^{2, 3}			9	
Ciss	Input Capacitance			25	
Coss	Output Capacitance	V _{DS} =30V , V _{GS} =0V , F=1MHz		15	 pF
Crss	Reverse Transfer Capacitance			6.8	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	Vg=VD=0V,Force Current			200	mA
Іѕм	Pulsed Source Current	VG-VD-0V , Force Current	-	-	400	mA
VsD	Diode Forward Voltage	V _G s=0V , I _S =0.1A , T _J =25°C			1	V
Trr	Reverse Recovery Time	V _R =50V, I _S =0.1A ,		18		ns
Qrr	Reverse Recovery Charge	dI/dt=100A/µs, TJ=25°C		6		nC

Note:

- Repetitive Rating : Pulsed width limited by maximum junction temperature. The data tested by pulsed , pulse width ≤ 300 us , duty cycle $\leq 2\%$. 1.
- 2.
- 3. Essentially independent of operating temperature.

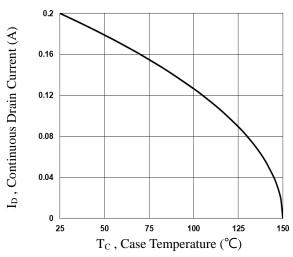


Fig.1 Continuous Drain Current vs. Tc

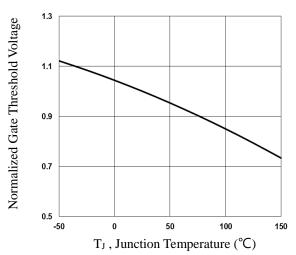


Fig.3 Normalized V_{th} vs. T_J

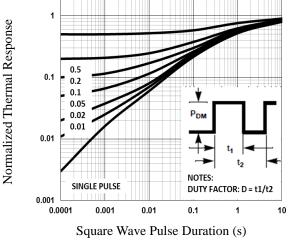


Fig.5 Normalized Transient Response

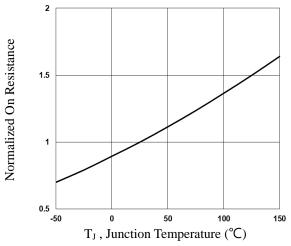


Fig.2 Normalized RDSON vs. T_J

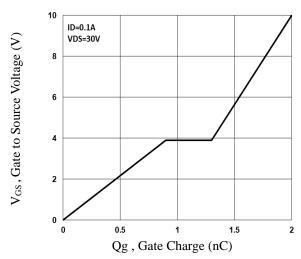


Fig.4 Gate Charge Waveform

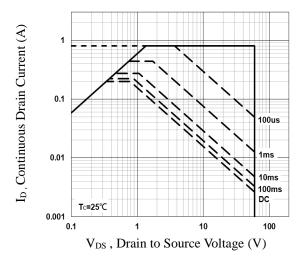
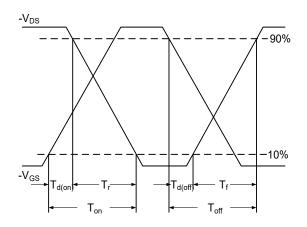


Fig.6 Maximum Safe Operation Area





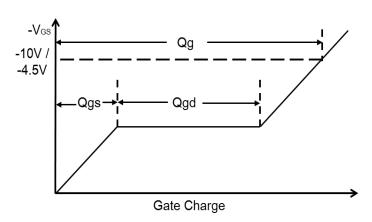
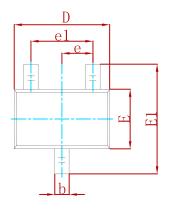
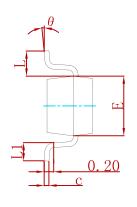


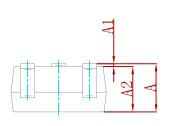
Fig.8 Gate Charge Waveform



PACKAGEMECHANICALDATA

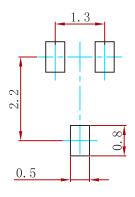






Symbol	Dimensions	Dimensions In Millimeters		s In Inches	
Syllibol	Min	Max	Min	Max	
Α	0.900	1.100	0.035	0.043	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.000	0.035	0.039	
b	0.200	0.400	0.008	0.016	
С	0.080	0.150	0.003	0.006	
D	2.000	2.200	0.079	0.087	
Е	1.150	1.350	0.045	0.053	
E1	2.150	2.450	0.085	0.096	
е	0.650 TYP		0.026 TYP		
e1	1.200	1.400	0.047	0.055	
L	0.525	REF	0.021 REF		
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

Suggested Pad Layout



Note:

- 1. Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
2N7002W	SOT-323	3000



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